

TRANSMITTAL LETTER
(General - Patent Pending)

Docket No.
06550001AA

In Re Application Of: Fay et al.

Serial No.
09/881,026

Filing Date
06/15/2002

Examiner
C. Young

Group Art Unit
1756

Title: AUTOMATED OVERLAY METROLOGY SYSTEM



TO THE COMMISSIONER OF PATENTS AND TRADEMARKS:

Transmitted herewith is:

Information Disclosure Statement
PTO-1449
2 cited references

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TC 1700

in the above identified application.

- ☐ No additional fee is required.
- ☒ A check in the amount of \$180.00 is attached.
- ☒ The Commissioner is hereby authorized to charge and credit Deposit Account No. 50-2041 as described below. A duplicate copy of this sheet is enclosed.
- ☐ Charge the amount of
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Signature

Dated: May 9, 2003

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PATENT TRADEMARK OFFICE

CC:

I certify that this document and fee is being deposited on _____ with the U.S. Postal Service as first class mail under 37 C.F.R. 1.8 and is addressed to the Commissioner of Patents and Trademarks, Washington, D.C. 20231.

Signature of Person Mailing Correspondence

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06550001AA

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re patent application of

Fay et al.

Serial No.: 09/881,026

Group Art Unit: 1756

Filed: June 15, 2002

Examiner: C. Young

For: AUTOMATED OVERLAY METROLOGY SYSTEM

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

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INFORMATION DISCLOSURE STATEMENT

Sir:

Under the provisions of 37 C.F.R. 1.97 through 1.99 and pursuant to applicant's duty of disclosure under 37 C.F.R. 1.56, applicant respectfully brings the following documents, listed on the attached form PTO-1449, to the attention of the Examiner in charge of the above-identified application. A copy of the listed documents is provided for the convenience of the Examiner

This citation does not constitute an admission that the references are relevant or material to the claims. They are only cited as constituting related art of which the applicant is aware.

This statement shall not be construed as a representation that a search has been made or that no other art than that identified exists.

It is respectfully requested that the listed references be considered by the Examiner and formally made of record in this application.

A check in the amount of \$180.00 to cover the fee as specified by 37 C.F.R. 1.17(p) is enclosed.

Respectfully submitted,

Marshall M. Curtis

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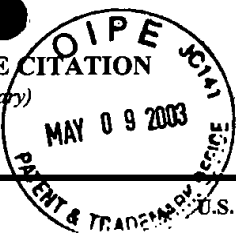
05/12/2003 WADDLELRI 00000029 09881026

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INFORMATION DISCLOSURE CITATION

(Use several sheets if necessary)



Docket Number (Optional)

06550001A

Application Number

09/881,026

Applicant(s)

Fay et al.

Filing Date

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Group Art Unit

1756

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE

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FOREIGN PATENT DOCUMENTS

	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
							YES	NO
		Abstract of 2001-272208	10/05/2001	Japan				

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

		Niu et al.; "Specular Spectroscopic Scatterometry in DUV Lithography"; SPIE Conference on Metrology, Inspection and Process Control for Microlithography XIII, Santa Clara, CA, March 1999; pgs. 159-168

EXAMINER

DATE CONSIDERED

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.